

### **In the Specification**

Please replace the following paragraph on page 12, lines 5-22 with the following clean replacement paragraph:

One consideration in selecting a material for the barrier layer is the thickness and density of the barrier layer that will be sufficient to achieve a desired level of oxygen diffusion reduction. Another factor to evaluate is that the barrier layer might be considered to form a part of a capacitor electrode when the barrier layer contacts one of the first or second electrodes since the barrier layer is conductive. Accordingly, it may be advantageous to recalculate the desired dimensions of an electrode contacted by the barrier layer accounting for the presence of the additional conductive material. Accordingly, a “conductive” material as the term is used herein designates a material exhibiting a conductivity at 20°C of greater than  $[[10^4]] \underline{10^{-12}}$  microOhm<sup>-1</sup> centimeter<sup>-1</sup>, or preferably greater than about  $[[10^{12}]] \underline{10^{-4}}$  microOhm<sup>-1</sup> centimeter<sup>-1</sup>. Notably, such definition expressly includes “semiconductive” material in the range of about  $[[10^4]] \underline{10^{-12}}$  to about  $[[10^{12}]] \underline{10^{-4}}$  microOhm<sup>-1</sup> centimeter<sup>-1</sup>. As an alternative, a “conductive” material in the present context might be viewed as a material that does not substantially impact the capacitance otherwise achieved without the material. Generally, an “insulative” material might produce a change in capacitance as such a barrier layer.